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TITLE **VDSL - Proposal for VDSL testloops**

STATUS Proposal, for discussion

ABSTRACT This contribution is a proposal for the VDSL testloop topologies, as requested at the Tel Aviv meeting. The proposal includes topology, specified insertion loss for the different bitrates, expressions, line constants and plots that demonstrate the purpose and impact of the testloops. When accepted, the text can be copied literally into the VDSL draft at paragraph 10.1.

10 VDSL Performance requirements

10.1 VDSL Test loops

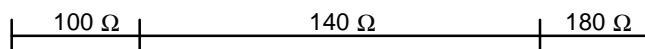
The purpose of the testloops in figure 1 is to stress VDSL modems in various ways, to test the VDSL performance under quasi realistic circumstances. Loop #0 is a symbolic name for a loop with zero length, to prove that VDSL can handle the signal levels when they are directly interconnected. Loop#0 is a simple representation of the shortest line that is in use in access networks.

All other testloops in figure 1 have equal insertion loss, but differ in input impedance.

- The impedances in loop 1 and 2 are nearly constant over a wide frequency interval. These two loops represent uniform distribution cables, one having a relatively low characteristic impedance and another having a relative high impedance. These impedance values are chosen to be the lowest and highest values of 0.5mm distribution cables that are *commonly* used in Europe.
- The impedances of loop 3 and 4 follow frequency curves that are oscillating in nature. This represents the mismatch effects in distribution cables caused by a short extent with a cable that differs significantly in characteristic impedance. Loop 3 represents this at the LT side to stress downstream signals only. Loop 4 does the same at the NT side to stress upstream signals only.

***Author suggestion:** Loop #3 represents a common Dutch situation where the underground distribution cable is extended in the central office by a commonly used indoor cable. Loop #4 represents, to our knowledge, a common British situation where the underground cable is extended by a dropwire (DW8). Loop #4 causes a severe mismatch (impedances oscillate between 100Ω and 250Ω) at the NT side that might reduce the upstream performance of VDSL modems significantly. When there is a strong demand on reducing the number of testloops, the stressing factors of loop #4 can be combined with loop #3 by extending the long 140Ω cable at the NT side with 180Ω. This mismatch is not as severe as in loop 4, but it might be a compromise to consider.*

The combination of [100Ω + 140Ω + 180Ω] lines is a reasonable compromise, that meets the requirement that both ends have a serious mismatch, similar to the LT side of loop#3 and the NT side of loop#4



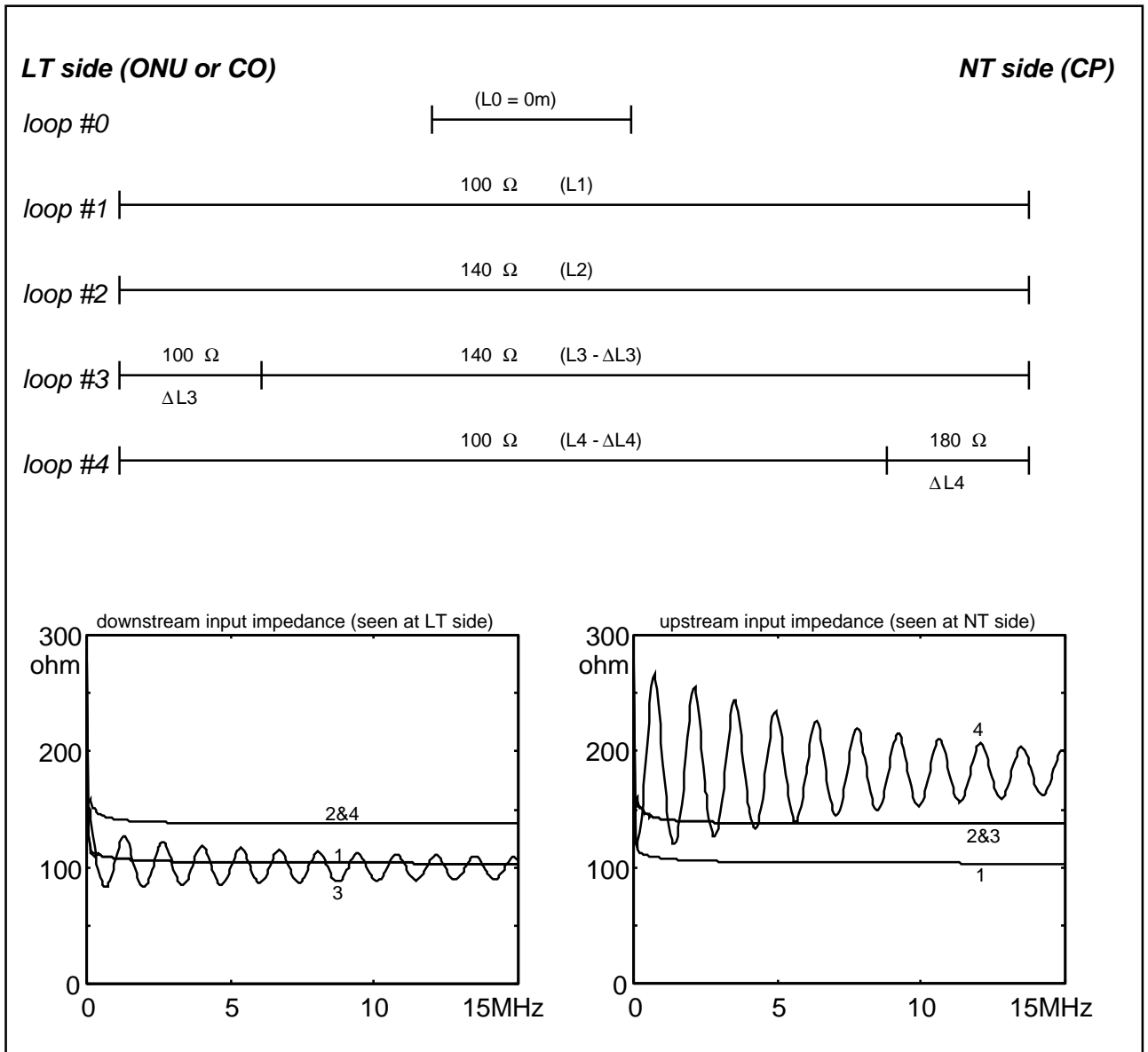


Figure 1. Test loop topology

For each VDSL bitrate, the virtual “length” of the individual testloops is defined in terms of a common insertion loss (at 135Ω), at a common frequency. This frequency is chosen to be a typical high-band frequency that is used for transporting that bitrate. The insertion loss is chosen as a typical maximum value that can be handled correctly by the VDSL modem. The higher the bitrate, the lower the insertion loss is that can be handled in practice. This is because the crosstalk in real cables increases with the frequency. Table 1 specifies these insertion loss values for the different VDSL bitrates.

Author comment: The text tries to explain in a top-down way what the purpose of the loops is, and why these loops fulfill their job. Any reference to cable diameter and physical cable length are made as low-profile as possible in this text. This to make clear that the loops are chosen because of their common use, characteristic impedance and insertion loss. The nominal length is nothing more than the result of insertion loss, not in reverse.

VDSL bitrate	test frequency f_H	insertion loss @135W, @ f_H
6.5 Mb/s	2.5 MHz	44 dB
13 Mb/s	4 MHz	38 dB
26 Mb/s	6 MHz	28 dB
52 Mb/s	8 MHz	17 dB

Table 1. Insertion loss for loop #1 to #4, specified for the individual bitrates.

Author note: At this point, we need input of VDSL manufacturers that have experience with VDSL simulations, to find out if these test frequencies are really representative as typical high-band frequency or not. The same applies for the chosen insertion loss values. To make a good start for a proposal, we have chosen them to be equivalent with loops of nearly 1500, 1000, 600 and 300 meters.

The different cable sections are specified by reference models [1], that serve as a template for real twisted-pair cables. The virtual lengths that meet the insertion loss requirements of table 1 are summarized in table 2. The associated models and line constants are specified in table 4, 5 and 6. Figure 2 shows the calculated transmission functions of the testloops, at 135Ω, to be used for the various VDSL bitrates.

test loop	distribution cable (L)	extention cable (DL) LT or NT side	virtual length DL	virtual length L (6.5Mb/s)	virtual length L (13 Mb/s)	virtual length L (26 MB/s)	virtual length L (52 Mb/s)
#0	--	--	--	0	0	0	0
#1	"A"	--	--	1496 m	1004 m	595 m	308 m
#2	"B"	--	--	1418 m	929 m	534 m	270 m
#3	"B"	"C"	70 m	1413 m	930 m	535 m	277 m
#4	"A"	"D"	70 m	1498 m	1002 m	585 m	292 m

Table 2. Calculated testloop length, that meets the insertion loss requirements in table 1, based on the cable models of table 4, 5 and 6. Dit following cables models [1] have been used as template for these testloops: A =BT_DWUG, B =KPN_L1, C =KPN_R2 and D =BT_DW8

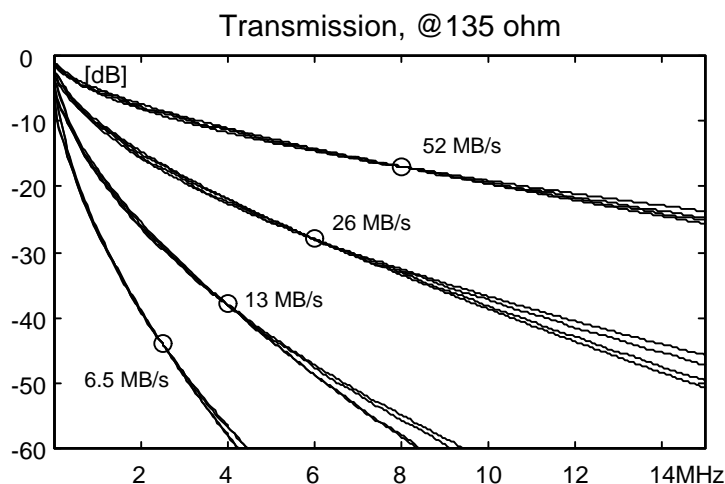


Figure 2. Transmission (@135W) of the testloops for various bitrates, calculated using the models and line constants of table 4, 5 and 6.

BT#0	$Z_s(f)$	$= \sqrt[4]{R_{oc}^4 + a_c \cdot f^2} + j \cdot 2\pi f \cdot \left(\frac{L_0 + L_{\infty} \cdot (f/f_m)^{N_b}}{1 + (f/f_m)^{N_b}} \right)$	[Ω/km]
	$Y_p(f)$	$= (g_0 \cdot f^{N_{ge}}) + j \cdot 2\pi f \cdot (C_{\infty} + C_0 / f^{N_{ce}})$	[S/km]
KPN#1	$Z_{s0}(\omega)$	$= j \cdot \omega \cdot Z_{0\infty} \cdot 1/c + R_{ss00} \cdot (1 + K_l \cdot K_f \cdot (\chi \cdot \coth(4/3 \cdot \chi) - 3/4))$	[Ω/m]
	$Y_{p0}(\omega)$	$= j \cdot \omega / Z_{0\infty} \cdot 1/c \cdot (1 + (K_c - 1) / (1 + (\omega/\omega_{c0})^N)) + \tan(\phi) / (Z_{0\infty} \cdot c) \cdot \omega^M$	[S/m]
$\chi = \chi(\omega) = (1+j) \cdot \sqrt{\frac{\omega}{2\pi} \cdot \frac{\mu_0}{R_{ss00}} \cdot \frac{1}{K_n \cdot K_f}}, \quad \omega_{c0} = 2\pi \cdot f_{c0}$			

Table 4. Formal models for the BT and the KPN cable parameters in the testloops

Wire type	R_{oc} N_b	a_c g_0	R_{os} N_{ge}	a_s C_o	L_o C_{\ddagger}	L_{\ddagger} N_{ce}	f_m
A	179	35.89e-3	0.0	0.0	0.695e-3	585e-6	1e6
	1.2	0.5e-9	1.033	1e-9	55e-9	0.1	
D	41.16	1.2179771e-3	0.0	0.0	1e-3	910.505e-6	174877.
	1.1952665	53.0e-9	0.88	31.778569e-9	22.681213e-9	0.11086674	

Table 5. Line constants for the BT cables in the testloops. The models are valid from DC to 30 MHz, when using these parameters.

	$Z_{0\infty}$	c/c_0	R_{ss00}	$2\pi \tan(\phi)$	K_f	K_l	K_n	K_c	N	f_{c0}	M
B	136.651	0.79766	0.168145	0.13115	0.72	1.2	1	1.08258	0.7	4521710	1
C	97.4969	0.639405	0.177728	0.0189898	0.5	1.14	1	1	1	100000	1

Table 6. Line constants for the KPN cables in the testloops. The models are valid from DC to 30 MHz, when using these parameters.

Author note: We should NOT start a political discussion on which cable model is the best of these two, just to save 4cm of text in the VDSL report. There are more models in use [1], and these models are OK when they do their job right. We are specifying loops here, not models, and the full two-port behaviour of the testloop cables should be defined from DC up to some upper frequency, say 30MHz. Models are no more than a vehicle to achieve this. So, when we agree on a cable for which an adequate model is available, then we should use that model.

References

- [1] Rob van den Brink: **Cable reference models for simulating metallic access networks**, ETSI-TM6 permanent document ETSI/STC TM6(97)02, [970p02r1], Berlin, Germany, 2-8 june 1997.